

ZXMN2F34FH 20V SOT23 N-channel enhancement mode MOSFET

Summary

V _{(BR)DSS}	$R_{DS(on)}\left(\Omega\right)$	I _D (A)
20	0.060 @ V _{GS} = 4.5V	4.0
	0.120 @ V _{GS} = 2.5V	2.9

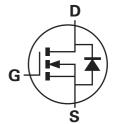


Description

This new generation Trench MOSFET from Zetex features low onresistance achievable with low (2.5V) gate drive.

Features

- · Low on-resistance
- · 2.5V gate drive capability
- SOT23 package

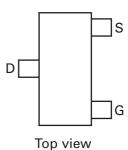


Applications

- Buck/Boost DC-DC Converters
- Motor Control
- · LED Lighting

Ordering information

DEVICE	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXMN2F34FHTA	7	8	3000



Device marking

KNB

Absolute maximum ratings

Parameter	Symbol	Limit	Unit
Drain source voltage	V _{DSS}	20	V
Gate source voltage	V _{GS}	±12	V
Continous Drain Current @ V _{GS} =4.5; T _A =25°C ^(b)	I _D	4.0	Α
@ V _{GS} =4.5; T _A =70°C ^(b)		3.3	Α
@ V _{GS} =4.5; T _A =25°C ^(a)		3.4	Α
Pulsed drain current ^(c)	I _{DM}	18.6	Α
Continuous source current (body diode)(b)	I _S	2.1	А
Pulsed source current (body diode)(c)	I _{SM}	18.6	Α
Power dissipation at T _A =25°C ^(a)	P _D	0.95	W
Linear derating factor		7.6	mW/°C
Power dissipation at T _A =25°C ^(b)	P _D	1.4	W
Linear derating factor		11	mW/°C
Operating and storage temperature range	T _j , T _{stg}	-55 to 150	°C

Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient ^(a)	$R_{ heta JA}$	131	°C/W
Junction to ambient ^(b)	$R_{\Theta JA}$	89	°C/W
Junction to lead ^(d)	$R_{ ext{OJL}}$	68	°C/W

NOTES

⁽a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

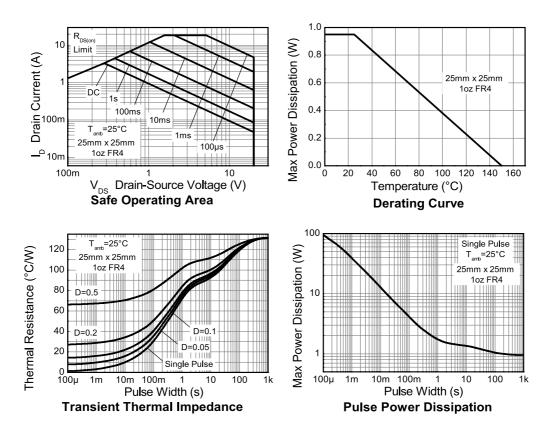
⁽b) For a device surface mounted on FR4 PCB measured at t $\! \leq \! 5$ sec.

⁽c) Repetitive rating - $25mm \times 25mm \text{ FR4 PCB}$, D=0.02, pulse width $300\mu\text{s}$ - pulse width limited by maximum junction temperature.

⁽d) Thermal resistance from junction to solder-point (at end of drain lead).

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Thermal characteristics



Electrical characteristics (at T_{amb} = 25°C unless otherwise stated)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions	
Static						•	
Drain-Source Breakdown Voltage	V _{(BR)DSS}	20			V	I _D = 250μA, V _{GS} =0V	
Zero Gate Voltage Drain Current	I _{DSS}			1	μΑ	V _{DS} = 20V, V _{GS} =0V	
Gate-Body Leakage	I _{GSS}			100	nA	V _{GS} =±12V, V _{DS} =0V	
Gate-Source Threshold Voltage	V _{GS(th)}	0.5	0.8	1.5	V	$I_D=250\mu A,V_{DS}=V_{GS}$	
Static Drain-Source On-State Resistance (*)	R _{DS(on)}			0.060 0.120	Ω Ω	V _{GS} = 4.5V, I _D = 2.5A V _{GS} = 2.5V, I _D = 1.0A	
Forward Transconductance ^{(*)(†)}	9 _{fs}		7.5		S	V _{DS} = 10V, I _D = 2.5A	
Dynamic (†)							
Input Capacitance	C _{iss}		277		pF		
Output Capacitance	C _{oss}		65		рF	V _{DS} = 10V, V _{GS} =0V f=1MHz	
Reverse Transfer Capacitance	C _{rss}		35		pF	- 1 - 11/11/12	
Switching (‡)(†)							
Turn-On-Delay Time	t _{d(on)}		2.65		ns		
Rise Time	t _r		4.2		ns	V _{DD} = 10V, V _{GS} = 4.5V I _D = 1A	
Turn-Off Delay Time	t _{d(off)}		9.9		ns	$R_{\rm G} \approx 6.0\Omega$	
Fall Time	t _f		5.1		ns		
Total Gate Charge	Q_g		2.8		nC	V _{DS} = 10V, V _{GS} = 4.5V	
Gate-Source Charge	Q_{gs}		0.61		nC	I _D = 2.5A	
Gate Drain Charge	O _{gd}		0.63		nC	1	
Source-drain diode			ı	ı			
Diode Forward Voltage ^(*)	V_{SD}	_	0.73	1.2	V	I _S = 1.25A, V _{GS} =0V	
Reverse recovery time ^(†)	t _{rr}		6.5		ns	T _j =25°C, I _F =1.65A	
Reverse recovery charge ^(†)	Q _{rr}		1.4		nC	di/dt=100A/μs	

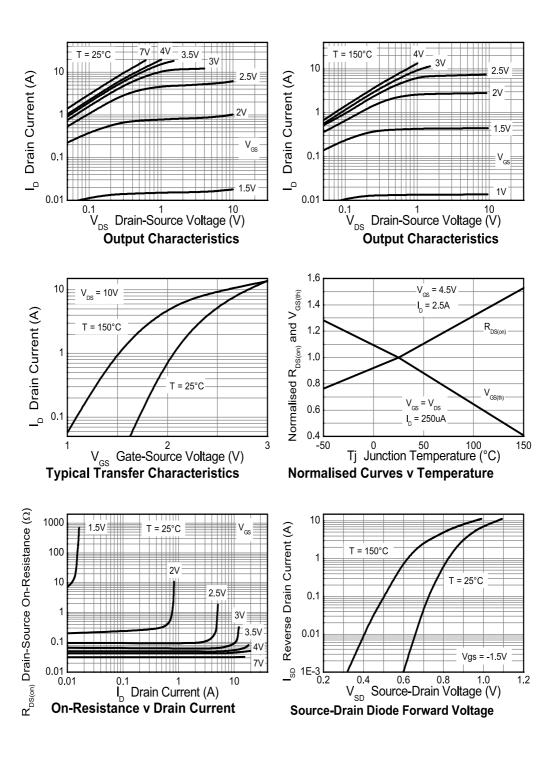
NOTES:

^(*) Measured under pulsed conditions. Pulse width \leq 300 μ s; duty cycle \leq 2%.

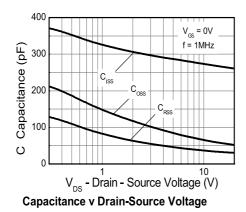
^(†) For design aid only, not subject to production testing.

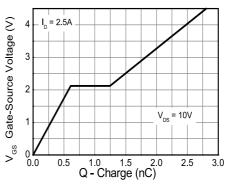
^(‡) Switching characteristics are independent of operating junction temperature.

Typical characteristics



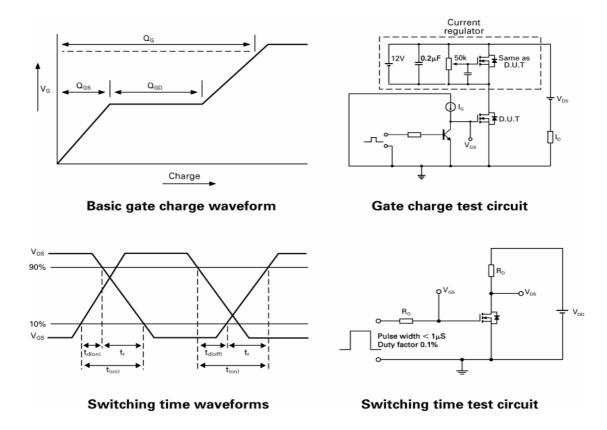
Typical characteristics





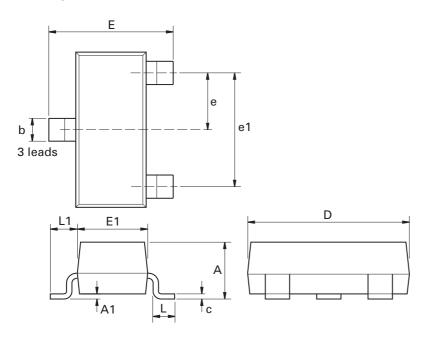
Gate-Source Voltage v Gate Charge

Test circuits



ZXMN2F34FH

Package outline - SOT23



Dim.	Millin	neters	Inc	hes	Dim.	Millimeters		Inches	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
Α	-	1.12	-	0.044	e1	1.90 NOM		0.075 NOM	
A1	0.01	0.10	0.0004	0.004	Е	2.10	2.64	0.083	0.104
b	0.30	0.50	0.012	0.020	E1	1.20	1.40	0.047	0.055
С	0.085	0.20	0.003	0.008	L	0.25	0.60	0.0098	0.0236
D	2.80	3.04	0.110	0.120	L1	0.45	0.62	0.018	0.024
е	0.95	NOM	0.037	NOM	-	-	-	-	-

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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